

Search Notes

Application/Control No.

10/046,940

Examiner

Ba Huynh

Applicant(s)/Patent under
Reexamination

BARKER ET AL.

Art Unit

2179

SEARCHED

Class	Subclass	Date	Examiner
715	760-767	10/17/2006	HB
	776,777		
717	100, 103		
	105, 120		
	140, 145		
	148, 168		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
All classes/subclasses above		10/17/2007	HB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East: USpat, USpgpub, Epo, Jpo, Derwent, IBM:tdb files search updated	10/17/2006	HB